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## TECHNICAL PROGRAM: ORAL PAPERS

### Session 1: Full Wave Modeling

Fast Direct Full-Wave Electromagnetic Analysis of Planar Circuits Embedded in Multilayered Media

A. Menshov<sup>1</sup>, V. Okhmatovski<sup>2</sup>, <sup>1</sup>*Dept. of ECE, The University of Texas at Austin, United States; <sup>2</sup>Dept. of ECE, University of Manitoba Winnipeg, MB, Canada*

A Fully 3-D BIE Evaluation of the Resistance and Inductance of On-Board and On-Chip Interconnects

M. Huynen, D. De Zutter, D. Vande Ginste, *Electromagnetics Group/IDLab, Department of Information Technology, Ghent University/imec, Gent, Belgium*

### Session 2: Macromodeling

Multivariate Macromodeling with Stability and Passivity Constraints

A. Zanco, S. Grivet-Talocia, T. Bradde, M. De Stefano, *Dept. Electronics and Telecommunications, Politecnico di Torino, Italy*

Reduced-Order Model for Time-Domain Sensitivity Analysis of Active Circuits

B. Nouri, M. Nakhla, *Department of Electronics, Carleton University, Ottawa, Canada*

Circuit Synthesis of Blackbox Macromodels from S-Parameter Representation

J. Schutt-Ainé, *Electrical and Computer Engineering, University of Illinois Urbana, USA*

### Session 3: Stochastic Analysis & Uncertainty Quantification

Uncertainty Quantification of SiP based Integrated Voltage Regulator

M. Larbi<sup>1</sup>, H. M. Torun<sup>1</sup>, M. Swaminathan<sup>1</sup>, I. S. Stievano<sup>2</sup>, F. G. Canavero<sup>2</sup>, P. Besnier<sup>3</sup>, <sup>1</sup>*Center for Co-Design of Chip, Package, System (C3PS), School of Electrical and Computer Engineering, Georgia Institute of Technology, Atlanta, US;* <sup>2</sup>*Dipartimento di Elettronica, Politecnico di Torino, Italy; <sup>3</sup>IETR, UMR CNRS 6164 : IETR, INSA de Rennes, France.*

Perturbative Statistical Assessment of PCB Differential Interconnects

X. Wu<sup>1</sup>, P. Manfredi<sup>2</sup>, F. Grassi<sup>1</sup>, D. Vande Ginste<sup>3</sup>, <sup>1</sup>*Dept. of Electronics, Information and Bioengineering, Politecnico di Milano, Italy;* <sup>2</sup>*Dept. of Electronics and Telecommunications, Politecnico di Torino, Italy;* <sup>3</sup>*Dept. of Information Technology, IDLab, Ghent University - imec, Belgium*

Modeling of Eye Diagram Height in High-Speed Links via Support Vector Machine

R. Trinchero, F. G. Canavero, *EMC Group, Department of Electronics and Telecommunications, Politecnico di Torino, Italy*

Parameterized Macromodeling of Stochastic Linear Systems for Frequency- and Time-Domain Variability Analysis

Y. Ye<sup>1</sup>, D. Spina<sup>1</sup>, G. Antonini<sup>2</sup>, T. Dhaene<sup>1</sup>, <sup>1</sup>IDLab, *Department of Information Technology, Ghent University - imec, Belgium; <sup>2</sup>UAq EMC Laboratory, Dipartimento di Ingegneria Industriale e dell'Informazione e di Economia, Universita degli Studi dell'Aquila, Italy.*

Machine Learning Methodology for Inferring Network S-parameters in the Presence of Variability

X. Ma, M. Raginsky, A. C. Cangellaris, *Department of Electrical and Computer Engineering University of Illinois, USA*

#### **Session 4: Power Delivery Networks**

Power Integrity Challenges of Re-designing a Mobile SoC with Fully Integrated Voltage Regulator to IoT Applications,

Y. F. Shen, *Internet of Things Group, Intel Corporation, Chandler, USA*

An On-Chip Load Model for Off-Chip PDN Analysis Considering Interdependency Between Supply Voltage, Current Profile and Clock Latency

J. Chen <sup>1</sup>, T. Kanamoto<sup>2</sup>, H. Kando<sup>3</sup>, M. Hashimoto<sup>1</sup>, <sup>1</sup>*Osaka University Osaka, Japan; <sup>2</sup>Hirosaki University Aomori, Japan; <sup>3</sup>Murata Manufacturing Co., Ltd. Kyoto, Japan*

A Robust Power Delivery Design Strategy For Platform on DIMM

D. M. García-Mora<sup>1</sup>, J. Kar<sup>2</sup>, I. Mendez-Soriano<sup>1</sup>, H. Morales-Espínosa<sup>1</sup>, <sup>1</sup>*Datacenter Package and Power Solutions Intel Guadalajara Design Center Guadalajara, Mexico; <sup>2</sup>Datacenter Package and Power Solutions Intel Corporation Santa Clara, CA, USA.*

Optimizing Phase Settings of High-Frequency Voltage Regulators for Power Delivery Applications

F. De Jesús Leal-Romo<sup>1</sup>, J. L. Silva-Perales<sup>2</sup>, C. López-Limón<sup>2</sup>, J. E. Rayas-Sánchez<sup>1</sup>, <sup>1</sup>*Department of Electronics, Systems, and Informatics, ITESO, The Jesuit University of Guadalajara Mexico; <sup>2</sup>Intel Corp. Zapopan, Jalisco, Mexico.*

Optimization of On-Package Decoupling Capacitors Considering System Variables

A. Sanna, G. Graziosi, *Back-End Manufacturing and Technology R&D, STMicroelectronics, Agrate Brianza, Italy*

### **Session 5: Nano, Optical and Wireless Interconnects**

Integrated Dipole Antennas and Propagation Channel on Siliconin Ka Band for WiNoC Applications

I. El Masri, T. Le Gouguec, P-M. Martin, R. Allanic, C. Quendo, *Lab-STICC/Université de Brest (UBO) UMR CNRS 6285 BREST, France*

Electrical properties of a graphene nanoplatelets composite as interposer for electronic packages

A. Maffucci<sup>1</sup>, L. Ferrigno<sup>1</sup>, M.D. Migliore<sup>1</sup>, D. Pinchera<sup>1</sup>, F. Schettino<sup>1</sup>, F. Micciulla<sup>2</sup>, S. Bellucci<sup>2</sup>, S. Maksimenko<sup>3</sup>, A. Paddubskay<sup>3</sup>, <sup>1,2</sup>D.I.E.I., *University of Cassino and Southern Lazio, Cassino, Italy*; <sup>3</sup>Institute for Nuclear Problems, Belarusian State University, Minsk, Belarus

A Comparison of Higher-Order Graded-Index MMI-Based Splitters in Thin Glass Sheets for PCB Integration

J-P. Roth, T. Kühler, E. Griese, *University of Siegen, Theoretical Electrical Engineering and Photonics H; Siegen, Germany*

### **Session 6: Noise reduction**

Suppression of Noise from Digital-to-Analog Coupling in Shielding Cavity

H-W. Chan, R-B. Wu, *EDAP Laboratory, Graduate Institute of Communication Engineering National Taiwan University, Taipei, Taiwan*

Miniaturized Wide-and Dual-Band Multilayer Electromagnetic Bandgap For Antenna Isolation and on-Package/PCB Noise Suppression

P. Bantavis, M. Le Roy, A. Perennec, R. Lababidi, D. Le Jeune, *Lab-STICC, UMR CNRS 6285, Université de Brest (UBO)/ENSTA-Bretagne, Brest, France*

### **Session 7: Equalization techniques**

Direct Prediction of Linear Equalization Coefficients Using Raised Cosine Pulse Shaping in Frequency Domain

T. Wendt, T. Reuschel, C. Schuster, *Hamburg University of Technology, Institute of Electromagnetic Theory, Hamburg, Germany*

## DDR5 Design Challenges

N. Bhagwath<sup>1</sup>, R. Wolff<sup>2</sup>, S. Ikeda<sup>3</sup>, E. Fujine<sup>4</sup>, R. Shibata<sup>4</sup>, Y. Sugaya<sup>3</sup>, M. Ono<sup>3</sup>,  
<sup>1</sup>*Mentor Graphics, a Siemens Business, Fremont, USA;* <sup>2</sup>*Micron Technology Boise, USA* ; <sup>3</sup>*Socionext Yokohama, Japan* ; <sup>4</sup>*Socionext Kasugai, Japan*

## An Eye Diagram Improvement Method using Simulation Annealing Algorithm

P-J. Li, T-L. Wu, *Department of Electrical Engineering and Graduate Institute of Communication Engineering, National Taiwan University, Taipei, Taiwan*

## Session 8: Measurements and characterization

### Usage of ESD Detector Circuit for Analyzing Soft Failures in IC cores

T. Ostermann, *Institute for Integrated Circuits/Department for Energy-Efficient Analog Circuits and Systems JKU Johannes Kepler University of Linz, Linz, Austria*

### Modelling and Validation of High-Current Surface-Mount Current-Sense Resistor

J. Bačmaga<sup>1</sup>, R. Blečić<sup>2</sup>, R. Gillon<sup>3</sup>, A. Barić<sup>1</sup>, <sup>1</sup>*University of Zagreb, Faculty of Electrical Engineering and Computing, Zagreb, Croatia*; <sup>2</sup> *KU Leuven, ESAT-TELEMIC, Leuven, Belgium*; <sup>3</sup>*ON Semiconductor, Westerring Oudenaarde, Belgium*

### Fast and Robust RF Characterization Method of Insulators used in High Speed Interconnects Networks

T. Lacreva<sup>1</sup>, D. Auchère<sup>2</sup>, G. Houzet<sup>1</sup>, P. Artillan<sup>1</sup>, B. Flechet<sup>1</sup>, C. Bermond<sup>1</sup>, B. Blampey<sup>1</sup>, <sup>1</sup>*IMEP-LAHC, UMR CNRS 5130, University Savoie Mont-Blanc, Le Bourget du Lac-France*; <sup>2</sup>*STMicroelectronics, Grenoble, France*

### In-Depth Characterization of a Dielectric Waveguide for mmW Transmission Line Applications

F. Distler, J. Schür, M. Vossiek, *Institute of Microwaves and Photonics (LHFT) Friedrich-Alexander-Universität Erlangen-Nürnberg (FAU) Erlangen, Germany*

## Session 9: High Speed links and modeling for SI/PI

### Physical Scaling Effects of Differential Crosstalk in Via Arrays up to Frequencies of 100 GHz

K. Scharff, D. Dahl, H-D. Brüns, C. Schuster, *Institute of Electromagnetic Theory, Hamburg University of Technology, Hamburg, Germany*

### Impact of Chip and Interposer PDN to Eye Diagram in High Speed Channels

F. De Paulis<sup>1</sup>, B. Zha<sup>2</sup>, S. Piersanti<sup>1</sup>, J. Cho<sup>2</sup>, R. Cecchetti<sup>1</sup>, B. Achkir<sup>3</sup>, A. Orlandi<sup>1</sup>, J. Fan<sup>2</sup>, <sup>1</sup>*University of L'Aquila L'Aquila, Italy*; <sup>2</sup> *MST EMC Laboratory Missouri University of Science and Technology Rolla, USA*; <sup>3</sup> *Cisco Systems San Jose, USA*

## Impact of On-Chip Multi-Layered Inductor on Signal and Power Integrity of Underlying Power-Ground Net

A. Tsuchiya<sup>1</sup>, A. Hiratsuka <sup>2</sup>, T. Inoue<sup>1</sup>, K. Kishine<sup>1</sup>, H. Onodera<sup>2</sup>, <sup>1</sup>*Dept. Electronic Systems Engineering The University of Shiga Prefecture Hikone, Japan*; <sup>2</sup>*Dept. Communications and Computer Engineering Kyoto University Kyoto, Japan.*

## TECHNICAL PROGRAM: POSTER PAPERS

### Impact of the Doped Areas Sizes in the Performances of Microwave SPST Switches Integrated in a Silicon Substrate

R. Allanic<sup>1</sup>, D. Le Berre<sup>1</sup>, Y. Quere<sup>1</sup>, C. Quendo<sup>1</sup>, D. Chouteau<sup>2</sup>, V. Grimal<sup>2</sup>, D. Valente<sup>2</sup>, J. Billoue<sup>2</sup>, <sup>1</sup>*Lab-STICC, Université de Brest (UBO) UMR CNRS 6285, Brest, France*; <sup>2</sup>*Laboratoire GREMAN", Université de Tours, France.*

### Eye Diagram Estimation and Equalizer Design Method for PAM4

W-J. Chang, R-B. Wu, *EDAP Laboratory, Graduate Institute of Communication Engineering National Taiwan University, Taipei, Taiwan*

### Powering a Remote Board and Sensors in an extreme environment - an optical solution

C. Diouf<sup>1</sup>, L. Ghisa<sup>1</sup>, R. Hamie<sup>1</sup>, V. Quintard<sup>1</sup>, M. Guegan<sup>1</sup>, A. Perennou<sup>1</sup>, L. Gautier<sup>2</sup>, M. Tardivel<sup>2</sup>, S. E. Barbot<sup>2</sup>, F. Colas<sup>2</sup>, <sup>1</sup>*Lab-STICC/ ENIB, UMR CNRS 6285 Brest, France*, <sup>2</sup>*IFREMER/RDT Centre de Brest, France*

### Evaluation and Comparison of Mounted Inductance for Decoupling Capacitor

B. Goral<sup>1</sup>, C. Gautier<sup>1</sup>, A. Amedeo<sup>2</sup>, <sup>1</sup>*ENS de Paris-Saclay Cachan, France*; <sup>2</sup>*Thales Communications and Security Cholet, France*

### CMOS Integrated 1 GHz Ring Oscillator with Injection-Locked Frequency Divider for Low Power PLL

J. Park, S. Chun, H. Choi, N. Kim, *School of ECE, Chungbuk National University Cheong-ju, Korea.*

### Impedance Measurement in Operating Conditions for PLC Applications

S. Sabo<sup>1</sup>, L. Pace <sup>1</sup>, J-C. Le Bunetel<sup>3</sup>, A-S. Descamps<sup>2</sup>, C. Batard<sup>2</sup>, N. Idir<sup>1</sup>, O. Mahamane, <sup>1</sup>*University of Lille France*, <sup>2</sup>*University of Nantes France*; <sup>3</sup>*University of Tours, France*

Assessment of Coupled Transmission Lines Embedded Between Imperfectly Matched Differential Circuit Stages

G. Mendez-Jeronimo, R. Torres-Torres, *National Institute of Astrophysics, Optics and Electronics Puebla, Mexico*

Analysis of PSIJ in the Presence of both Ground-Bounce and Transmission Media

J. Narayan Tripathi<sup>1</sup>, A. Jain <sup>2</sup>, M. Marinkovic<sup>2</sup>, R. Achar<sup>2</sup>, <sup>1</sup>TD&P, STMicroelectronics, INDIA. <sup>2</sup>Department of Electronics, Carleton University, Ottawa, Canada.

Simulation of Nonuniform Coupled Transmission Lines using approximated S-Parameters Model.

A. Wardzinska, W. Bandurski, *Poznan University of Technology, Faculty of Electronics and Telecommunications, Poznań, Poland*